

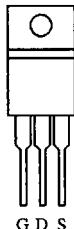
Siliconix

N-Channel Enhancement-Mode Transistor, 18-mΩ r_{DS(on)}**175°C Maximum Junction Temperature^a****Product Summary**

V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A)
60	0.018	60

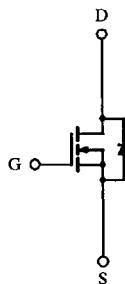
See lower-cost version: SUP50N06-18

TO-220AB



DRAIN connected to TAB

Top View



N-Channel MOSFET

Absolute Maximum Ratings (T_C = 25°C Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit	
Gate-Source Voltage	V _{GS}	± 20	V	
Continuous Drain Current	I _D	60	A	
		41		
Pulsed Drain Current	I _{DM}	240		
Avalanche Current	I _{AR}	60		
Avalanche Energy	L = 0.1 mH	I _{AR}	180	mJ
Repetitive Avalanche Energy ^a	L = 0.1 mH	E _{AR}	90	
Power Dissipation	P _D	125	W	
		62		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 175	°C	
Lead Temperature (1/16" from case for 10 sec.)	T _L	300		

Thermal Resistance Ratings

Parameter	Symbol	Typical	Maximum	Unit
Junction-to-Ambient	R _{thJA}		80	°C/W
Junction-to-Case	R _{thJC}		1.2	
Case-to-Sink	R _{thCS}	1.0		

Notes:

a. Duty cycle ≤ 1%

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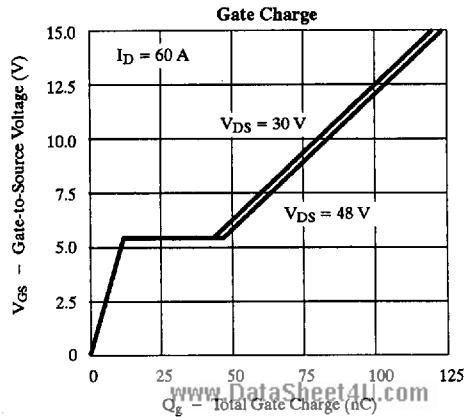
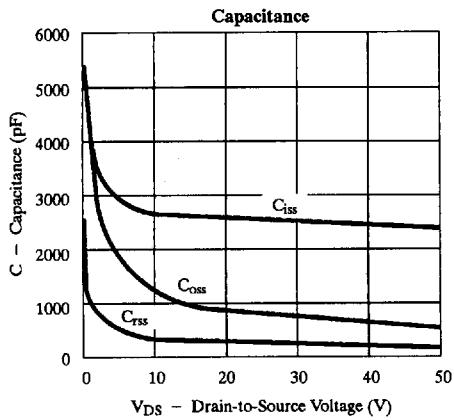
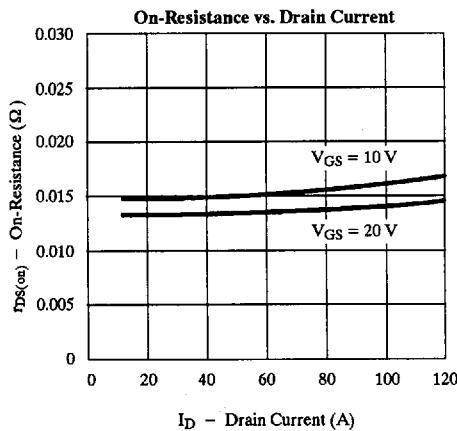
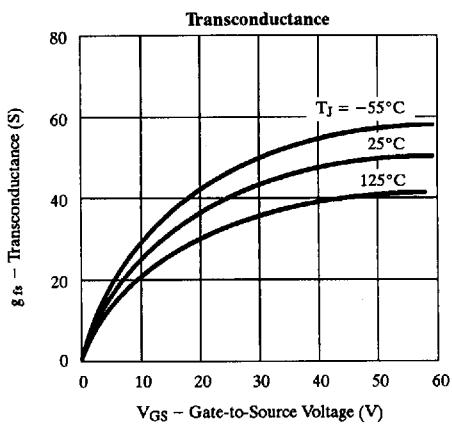
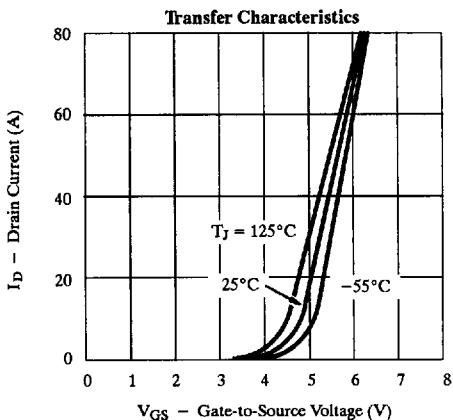
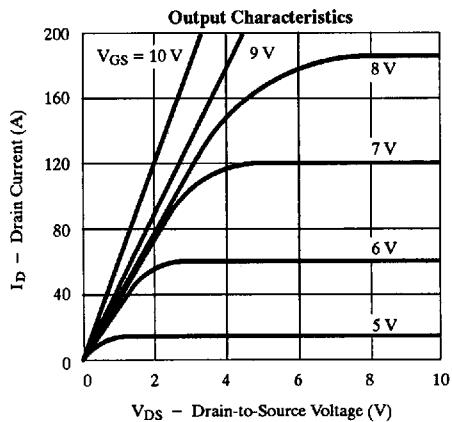
Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ ^a	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_{DS} = 1 \text{ mA}$	2.0		4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 500	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}$			25	μA
		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			250	
		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			500	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}$	60			A
Drain-Source On-State Resistance ^b	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.013	0.018	Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$		0.023	0.030	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$		0.026	0.036	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$		45		S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		2600		pF
Output Capacitance	C_{oss}			800		
Reversen Transfer Capacitance	C_{rss}			200		
Total Gate Charge ^c	Q_g	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		85	100	nC
Gate-Source Charge ^c	Q_{gs}			15	20	
Gate-Drain Charge ^c	Q_{gd}			35	50	
Turn-On Delay Time ^c	$t_{d(on)}$	$V_{DD} = 30 \text{ V}, R_L = 1 \Omega$ $I_D \approx 30 \text{ A}, V_{GRN} = 10 \text{ V}, R_G = 2.5 \Omega$		15	30	ns
Rise Time ^c	t_r			20	35	
Turn-Off Delay Time ^c	$t_{d(off)}$			50	65	
Fall Time ^c	t_f			20	30	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)						
Continuous Current	I_s				60	A
Pulsed Current	I_{SM}				240	
Forward Voltage ^b	V_{SD}	$I_F = 60 \text{ A}, V_{GS} = 0 \text{ V}$			2.0	V
Reverse Recovery Time	t_{rr}	$I_F = 60 \text{ A}, dI_F/dt = 100 \text{ A}/\mu\text{s}$			160	ns
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$				13	
Reverse Recovery Charge	Q_{rr}				1.0	μC

Notes:

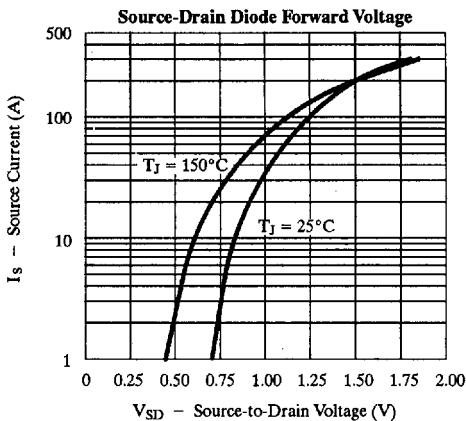
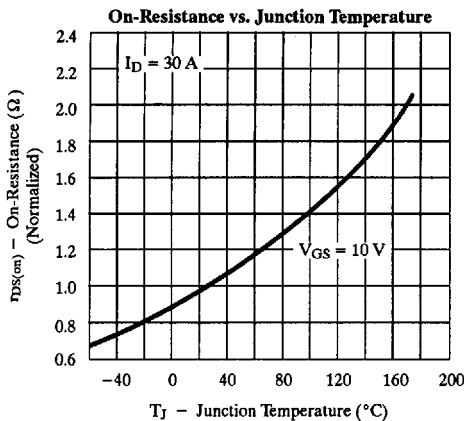
- a. For design aid only; not subject to production testing.
- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- c. Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



SMP60N06-18

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Typical Characteristics (25°C Unless Otherwise Noted)**Thermal Ratings**